INTEGRATED CIRCUITS



Product data Supersedes data of 2002 Dec 13 2003 Jul 31





FEATURES

- ESD classification testing is done to JEDEC Standard JESD22. Protection exceeds 2000 V to HBM per method A114.
- Latch-up testing is done to JEDEC Standard JESD78 which exceeds 100 mA
- Optimized for clock distribution in DDR (Double Data Rate) SDRAM applications as per JEDEC specifications
- 1-to-10 differential clock distribution
- Very low skew (< 100 ps) and jitter (< 100 ps)
- Operation from 2.2 V to 2.7 V AV_{DD} and 2.3 V to 2.7 V V_{DD}
- SSTL_2 interface clock inputs and outputs
- CMOS control signal input
- Test mode enables buffers while disabling PLL
- Low current power-down mode
- Tolerant of Spread Spectrum input clock
- Full DDR solution provided when used with SSTL16877 or SSTV16857
- Designed for DDR 266, 300, and 333 DIMM applications
- Available in TSSOP-48 and TVSOP-48 packages

DESCRIPTION

The PCKV857A is a high-performance, low-skew, low-jitter zero delay buffer designed for 2.5 V V_{DD} and 2.5 V AV_{DD} operation and differential data input and output levels.

The PCKV857A is a zero delay buffer that distributes a differential clock input pair (CLK, $\overline{\text{CLK}}$) to ten differential pairs of clock outputs (Y[0:9], Y[0:9]) and one differential pair feedback clock outputs (FB_{OUT}, $\overline{\text{FB}_{\text{OUT}}}$). The clock outputs are controlled by the clock inputs (CLK, $\overline{\text{CLK}}$), the feedback clocks (FB_{IN}, $\overline{\text{FB}_{\text{IN}}}$), and the analog power input (AV_{DD}). When PWRDWN is HIGH, the outputs switch in phase and frequency with CLK. When PWRDWN is LOW, all outputs are disabled to HIGH impedance state (3-State), and the PLL is shut down (LOW power mode). The device also enters the LOW power mode when the input frequency falls below 20 MHz. An input frequency detection circuit will detect the LOW frequency condition and after applying a > 20 MHz input signal, the detection circuit turns on the PLL again and enables the outputs.

When AV_{DD} is grounded, the PLL is turned off and bypassed for test purposes. The PCKV857A is also able to track spread spectrum clocking for reduced EMI.

The PCKV857A is characterized for operation from 0 to +70 °C.

ORDERING INFORMATION

PACKAGES	PACKAGES TEMPERATURE RANGE ORDER		DRAWING NUMBER
48-Pin Plastic TSSOP	0 to +70 °C	PCKV857ADGG	SOT362-1
48-Pin Plastic TSSOP (TVSOP)	0 to +70 °C	PCKV857ADGV	SOT480-1

г	
GND 1	48 GND
Y ₀ 2	47 Y ₅
Y ₀ 3	46 Y ₅
V _{DDQ} 4	45 VDDQ
Y ₁ 5	44 Y ₆
Y ₁ 6	43 Y ₆
GND 7	42 GND
GND 8	41 GND
₹2 9	40 Y ₇
Y ₂ 10	39 Y ₇
V _{DDQ} 11	38 VDDQ
V _{DDQ} 12	37 PWRDWN
CLK 13	36 FB _{IN}
CLK 14	35 FBIN
VDDQ 15	34 V _{DDQ}
AV _{DD} 16	33 FBOUT
AGND 17	32 FB _{OUT}
GND 18	31 GND
Y ₃ 19	30 Y ₈
Y ₃ 20	29 Y ₈
V _{DDQ} 21	29 Y ₈ 28 V _{DDQ}
Y ₄ 22	27 Y ₉
¥4 23	26 Y ₉
GND 24	25 GND
L	SW00691

PIN CONFIGURATION

Product data

PIN DESCRIPTION

PINS	SYMBOL	DESCRIPTION
1, 7, 8, 18, 24, 25, 31, 41, 42, 48	GND	SSTL_2 ground pins
2, 3, 5, 6, 9, 10, 19, 20, 22, 23, 26, 27, 29, 30, 32, 33, 39, 40, 43, 44, 46, 47	$Y_n, \overline{Y}_n, FB_{OUT}, \overline{FB_{OUT}}$	SSTL_2 differential outputs
4, 11, 12, 15, 21, 28, 34, 38, 46	V _{DDQ}	SSTL_2 power pins
13, 14, 35, 36	CLK _{IN} , CLK _{IN} , FB _{IN} , FB _{IN}	SSTL_2 differential inputs
16	AV _{DD}	Analog power
17	AGND	Analog ground
37	PWRDWN	Power-down control input

FUNCTION TABLE

	INPUTS			OUTPUTS			
PWRDWN	CLK	CLK	Υ _n	∀ n	FB _{OUT}	FB _{OUT}	PLL ON/OFF
L	L	н	Z	Z	Z ¹	Z ¹	OFF
L	Н	L	Z	Z	Z ¹	Z ¹	OFF
Н	L	Н	L	Н	L	Н	ON
Н	Н	L	Н	L	н	L	ON
X ²	< 20 MHz	< 20 MHz	Z	Z	Z ¹	Z ¹	OFF

NOTES:

H = HIGH voltage level L = LOW voltage level

Z = HIGH impedance OFF-state

X = don't care

Subject to change. May cause conflict with FB_{IN} pins.
 Additional feature that senses when the clock input is less than 20 MHz and places the part in sleep mode.

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS¹

	DADAMETED		LIN	LIMITS		
SYMBOL	PARAMETER	CONDITION	MIN	MAX	UNIT	
V _{DDQ}	Supply voltage range		0.5	3.6	V	
AV _{DD}	Supply voltage range		0.5	3.6	V	
VI	Input voltage range	see Notes 2 and 3	-0.5	$V_{DDQ} + 0.5$	V	
Vo	Output voltage range	see Notes 2 and 3	-0.5	$V_{DDQ} + 0.5$	V	
I _{IK}	Input clamp current	$V_{I} < 0$ or $V_{I} > V_{DDQ}$	—	±50	mA	
I _{OK}	Output clamp current	V_{O} < 0 or V_{O} > V_{DDQ}	—	±50	mA	
Ι _Ο	Continuous output current	$V_{O} = 0$ to V_{DDQ}	—	±50	mA	
	Continuous current to GND or V _{DDQ}		_	±100	mA	
T _{stg}	Storage temperature range		-65	+150	°C	

NOTES:

1. Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The input and output negative voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

3. This value is limited to 3.6 V maximum.

RECOMMENDED OPERATING CONDITIONS¹

SYMBOL	PARAMETER		CONDITION	LIMITS			
SYMBOL	PARAMETER	CONDITION		MIN	TYP	MAX	UNIT
V _{DDQ}	Supply voltage range			2.3	_	2.7	V
AV _{DD}	Supply voltage range			2.2	_	2.7	V
VIL	LOW-level input voltage	CLK, <u>CLK,</u> FB _{IN} , FB _{IN}		_	_	V _{DDQ} /2 - 0.18	v
		PWRDWN		-0.3	—	0.7	
V _{IH}	HIGH-level input voltage	CLK, <u>CLK,</u> FB _{IN} , FB _{IN}		V _{DDQ} /2 + 0.18	_	_	v
		PWRDWN		1.7	—	$V_{DDQ} + 0.3$	
	DC input signal voltage	-	Note 2	-0.3	_	V _{DDQ}	V
M	DC differential input signal voltage	CLK, FB _{IN}	Note 3	0.36	_	V _{DDQ} + 0.6	V
V _{ID}	AC differential input signal voltage	CLK, FB _{IN}	Note 3	0.7	—	$V_{DDQ} + 0.6$	V
V _{OX}	Output differential cross-voltage	-	Note 4	$V_{DDQ}/2 - 0.2$	V _{DDQ} /2	$V_{DDQ}/2 + 0.2$	V
V _{IX}	Input differential cross-voltage		Note 4	$V_{DDQ}/2 - 0.2$	—	$V_{DDQ}/2 + 0.2$	V
I _{OH}	HIGH-level output current			—	—	-12	mA
I _{OL}	LOW-level output current			—	—	12	mA
SR	Input slew rate			1	—	4	V/ns
T _{amb}	Operating free-air temperature			0	_	70	°C

NOTES:

1. Unused inputs must be held HIGH or LOW to prevent them from floating.

 DC input signal voltage specifies the allowable DC execution of differential input.
 Differential input signal voltage specifies the differential voltage |VTR - VCP| required for switching, where VTR is the true input level and VCP is the complementary input level.

4. Differential cross-point voltage is expected to track variations of V_{CC} and is the voltage at which the differential signals must be crossing.

DC ELECTRICAL CHARACTERISTICS

Over recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

	DADAMETED					
SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{IK}	Input voltage, all inputs	V _{DDQ} = 2.3 V, I _I = -18 mA		_	-1.2	V
M		V_{DDQ} = min to max, I_{OH} = -1 mA	V _{DDQ} - 0.1	_	—	V
V _{OH}	HIGH-level output voltage	$V_{DDQ} = 2.3 \text{ V}, I_{OH} = -12 \text{ mA}$	1.7	_	—	V
		V_{DDQ} = min to max, I_{OL} = 1 mA	_	_	0.1	V
V _{OL}	LOW-level output voltage	V _{DDQ} = 2.3 V, I _{OL} = 12 mA	_	_	0.6	V
lı	Input current	$V_{DDQ} = 2.7 \text{ V}, \text{ V}_{I} = 0 \text{ V} \text{ to } 2.7 \text{ V}$		_	±10	μA
I _{OZ}	HIGH-impedance-state output current	$V_{DDQ} = 2.7 \text{ V}, V_O = V_{DDQ} \text{ or GND}$	_	_	±10	μA
I _{DDPD}	Power-down current on $V_{DDQ} + AV_{DD}$	CLK and $\overline{\text{CLK}} = 0 \text{ MHz}$, $\overline{\text{PWRDWN}} = \text{LOW}$; $\Sigma \text{ of } I_{\text{DD}} \text{ and } \text{AI}_{\text{DD}}$	_	30	100	μΑ
I _{DD}	Dynamic current on V _{DDQ}	$f_O = 67 \text{ MHz}$ to 190 MHz		200	300	mA
AI _{DD}	Supply current on AV _{DD}	f _O = 67 MHz to 190 MHz	—	8	10	mA
Cl	Input capacitance	V_{CC} = 2.5 V, V_{I} = V_{CC} or GND	2	2.8	3	pF

NOTE:

1. This is intended to operate in the SSTL_2 type IV unterminated mode without series resistors on the outputs.

All typical values are at respective nominal V_{DDQ}.
 Differential cross-point voltage is expected to track variations of V_{DDQ} and is the voltage at which the differential signals must be crossing.

TIMING REQUIREMENTS

Over recommended ranges of supply voltage and operating free-air temperature.

SYMBOL	PARAMETER	MIN	MAX	UNIT
fск	Operating clock frequency	100	250	MHz
	Input clock duty cycle	40	60	%
	Stabilization time ¹	100		μs

NOTE:

1. Time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal after power-up.

AC CHARACTERISTICS

GND = 0 V; t_r = t_f \leq 2.5 ns; C_L = 50 pF; R_L = 1 $k\Omega$

CYMDOL	DADAMETED	MAYEEODM	CONDITION				
SYMBOL	PARAMETER	WAVEFORM	CONDITION	MIN	TYP	MAX	UNIT
t _(O)	Static phase offset	Figure 1		-350	0	350	ps
t _{SK(O)}				_		150	ps
t _{SLR(O)}	t _{SLR(O)} Output clock slew rate			1		2	V/ns
t _{JIT(PER)}	JIT(PER) Jitter (period)		f_{O} = 67 MHz to 200 MHz	-75		75	ps
t _{JIT(CC)}	JIT(CC) Jitter (cycle-to-cycle)		f_{O} = 67 MHz to 200 MHz	-75		75	ps
t _{JIT(HPER)}	t _{JIT(HPER)} Half-period jitter			-75		75	ps
t _{PLH} 1 LOW to HIGH level propagation delay			Test mode/CLK to any output	_	3.7	_	ns
t _{PHL} ¹ HIGH to LOW level propagation delay			Test mode/CLK to any output	_	3.7	_	ns

NOTE:

1. Refers to transition of noninverting output.



AC WAVEFORMS



Figure 1. Static phase offset







Figure 3. Input and output slew rates

PCKV857A



Figure 4. Period jitter



Figure 5. Cycle-to-cycle jitter



Figure 6. Half-period jitter



Figure 7. Skew between any two outputs.

PCKV857A



Figure 8. Duty cycle limits and measurement

TEST CIRCUIT



Figure 9. Output load test circuit



PCKV857A

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Product data

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Product data

REVISION HISTORY

Rev	Date	Description
_2	20030731	Product data (9397 750 11759); ECN 853-2394 30057 dated 18 June 2003. Supersedes data of 2002 Decemaber 13 (9397 750 10867).
		Modifications:
		 Minor changes or corrections to existing product specifications.
_1	20021213	Product data (9397 750 10867); ECN 853-2394 29181 of 13 December 2002.

PCKV857A

Data sheet status

Level	Data sheet status ^[1]	Product status ^{[2] [3]}	Definitions
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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[3] For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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